

<b>Notice of References Cited</b>	Application/Control No. 10/581,117	Applicant(s)/Patent Under Reexamination VAN GASSEL ET AL.	
	Examiner Steven G. Snyder	Art Unit 2184	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0145239	07-2003	Kever et al.	713/300
*	B	US-6,061,732	05-2000	Korst et al.	709/231
*	C	US-2001/0003207	06-2001	KLING et al.	713/320
*	D	US-5,928,365	07-1999	Yoshida, Hideki	713/324
*	E	US-5,712,976	01-1998	Falcon et al.	725/115
*	F	US-7,100,013	08-2006	de Waal, Abraham B.	711/170
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2005025364 A	01-2005	Japan	AOKI, TAKASHI	
	O	JP 05012895 A	01-1993	Japan	HOTTA, YASUHIRO	
	P	JP 60224186 A	11-1985	Japan	GONDO et al.	
	Q	JP 10340519 A	12-1998	Japan	KASEBAYASHI, YUU	
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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